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| <b>Notice of References Cited</b> | Application/Control No.<br>09/814,071 | Applicant(s)/Patent Under<br>Reexamination<br>SUGIMOTO ET AL. |             |
|                                   | Examiner<br>Aaron C Perez-Daple       | Art Unit<br>2121  | Page 1 of 2 |

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Application/Control No.

09/814,071

Applicant(s)/Patent Under  
Reexamination  
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Examiner

Aaron C Perez-Daple

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Page 2 of 2

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